

IRFB20N50KPbF

SMPS MOSFET HEXFET® Power MOSFET

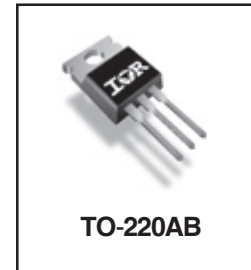
Applications

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits
- Lead-Free

| | | |
|------------------------|--------------------------------|----------------------|
| V_{DSS} | R_{DS(on)} typ. | I_D |
| 500V | 0.21Ω | 20A |

Benefits

- Low Gate Charge Q_g results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dv/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Low R_{DS(on)}



Absolute Maximum Ratings

| | Parameter | Max. | Units |
|---|---|--------------|-------|
| I _D @ T _C = 25°C | Continuous Drain Current, V _{GS} @ 10V | 20 | A |
| I _D @ T _C = 100°C | Continuous Drain Current, V _{GS} @ 10V | 12 | |
| I _{DM} | Pulsed Drain Current ① | 80 | |
| P _D @ T _C = 25°C | Power Dissipation | 280 | W |
| | Linear Derating Factor | 2.2 | W/°C |
| V _{GS} | Gate-to-Source Voltage | ± 30 | V |
| dv/dt | Peak Diode Recovery dv/dt ③ | 6.9 | V/ns |
| T _J | Operating Junction and | -55 to + 150 | |
| T _{STG} | Storage Temperature Range | | |
| | Soldering Temperature, for 10 seconds (1.6mm from case) | 300 | °C |
| | Mounting Torque, 6-32 or M3 screw | 10 | N |

Avalanche Characteristics

| Symbol | Parameter | Typ. | Max. | Units |
|-----------------|--------------------------------|------|------|-------|
| E _{AS} | Single Pulse Avalanche Energy② | — | 330 | mJ |
| I _{AR} | Avalanche Current④ | — | 20 | A |
| E _{AR} | Repetitive Avalanche Energy④ | — | 28 | mJ |

Thermal Resistance

| Symbol | Parameter | Typ. | Max. | Units |
|------------------|-------------------------------------|------|------|-------|
| R _{θJC} | Junction-to-Case | — | 0.45 | °C/W |
| R _{θCS} | Case-to-Sink, Flat, Greased Surface | 0.50 | — | |
| R _{θJA} | Junction-to-Ambient | — | 58 | |

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International
IR Rectifier

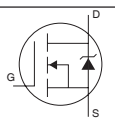
Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

| Symbol | Parameter | Min. | Typ. | Max. | Units | Conditions |
|---------------------------------|--------------------------------------|------|------|------|----------|---|
| $V_{(BR)DSS}$ | Drain-to-Source Breakdown Voltage | 500 | — | — | V | $V_{GS} = 0V, I_D = 250\mu A$ |
| $\Delta V_{(BR)DSS}/\Delta T_J$ | Breakdown Voltage Temp. Coefficient | — | 0.61 | — | V/°C | Reference to $25^\circ\text{C}, I_D = 1\text{mA}$ |
| $R_{DS(on)}$ | Static Drain-to-Source On-Resistance | — | 0.21 | 0.25 | Ω | $V_{GS} = 10V, I_D = 12A$ ④ |
| $V_{GS(th)}$ | Gate Threshold Voltage | 3.0 | — | 5.0 | V | $V_{DS} = V_{GS}, I_D = 250\mu A$ |
| I_{DSS} | Drain-to-Source Leakage Current | — | — | 50 | μA | $V_{DS} = 500V, V_{GS} = 0V$ |
| | | — | — | 250 | μA | $V_{DS} = 400V, V_{GS} = 0V, T_J = 125^\circ\text{C}$ |
| I_{GSS} | Gate-to-Source Forward Leakage | — | — | 100 | nA | $V_{GS} = 30V$ |
| | Gate-to-Source Reverse Leakage | — | — | -100 | nA | $V_{GS} = -30V$ |

Dynamic @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

| Symbol | Parameter | Min. | Typ. | Max. | Units | Conditions |
|------------------------|---------------------------------|------|------|------|-------|---|
| g_{fs} | Forward Transconductance | 11 | — | — | S | $V_{DS} = 50V, I_D = 12A$ |
| Q_g | Total Gate Charge | — | — | 110 | nC | $I_D = 20A$ |
| Q_{gs} | Gate-to-Source Charge | — | — | 33 | | $V_{DS} = 400V$ |
| Q_{gd} | Gate-to-Drain ("Miller") Charge | — | — | 54 | | $V_{GS} = 10V, \text{See Fig. 6 and 13}$ ④ |
| $t_{d(on)}$ | Turn-On Delay Time | — | 22 | — | ns | $V_{DD} = 250V$ |
| t_r | Rise Time | — | 74 | — | | $I_D = 20A$ |
| $t_{d(off)}$ | Turn-Off Delay Time | — | 45 | — | | $R_G = 7.5\Omega$ |
| t_f | Fall Time | — | 33 | — | | $V_{GS} = 10V, \text{See Fig. 10}$ ④ |
| C_{iss} | Input Capacitance | — | 2870 | — | pF | $V_{GS} = 0V$ |
| C_{oss} | Output Capacitance | — | 320 | — | | $V_{DS} = 25V$ |
| C_{rss} | Reverse Transfer Capacitance | — | 34 | — | | $f = 1.0\text{MHz}, \text{See Fig. 5}$ |
| C_{oss} | Output Capacitance | — | 3480 | — | | $V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0\text{MHz}$ |
| C_{oss} | Output Capacitance | — | 85 | — | | $V_{GS} = 0V, V_{DS} = 400V, f = 1.0\text{MHz}$ |
| $C_{oss \text{ eff.}}$ | Effective Output Capacitance | — | 160 | — | | $V_{GS} = 0V, V_{DS} = 0V \text{ to } 400V$ ⑤ |

Diode Characteristics

| Symbol | Parameter | Min. | Typ. | Max. | Units | Conditions |
|----------|--|---|------|------|---------|--|
| I_S | Continuous Source Current (Body Diode) | — | — | 20 | A | MOSFET symbol showing the integral reverse p-n junction diode.  |
| I_{SM} | Pulsed Source Current (Body Diode) ① | — | — | 80 | | |
| V_{SD} | Diode Forward Voltage | — | — | 1.5 | V | $T_J = 25^\circ\text{C}, I_S = 20A, V_{GS} = 0V$ ④ |
| t_{rr} | Reverse Recovery Time | — | 520 | 780 | ns | $T_J = 25^\circ\text{C}, I_F = 20A$ |
| Q_{rr} | Reverse Recovery Charge | — | 5.3 | 8.0 | μC | $di/dt = 100A/\mu s$ ④ |
| t_{on} | Forward Turn-On Time | Intrinsic turn-on time is negligible (turn-on is dominated by $L_S + L_D$) | | | | |

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting $T_J = 25^\circ\text{C}, L = 1.6\text{mH}, R_G = 25\Omega, I_{AS} = 20A,$
- ③ $I_{SD} \leq 20A, di/dt \leq 350A/\mu s, V_{DD} \leq V_{(BR)DSS}, T_J \leq 150^\circ\text{C}$
- ④ Pulse width $\leq 400\mu s$; duty cycle $\leq 2\%$.

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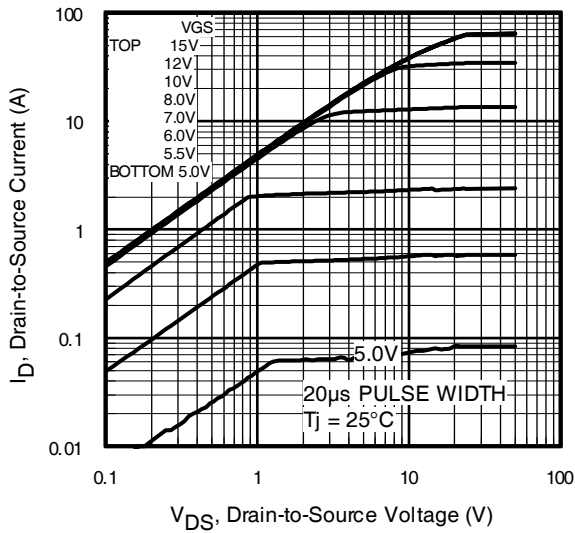


Fig 1. Typical Output Characteristics

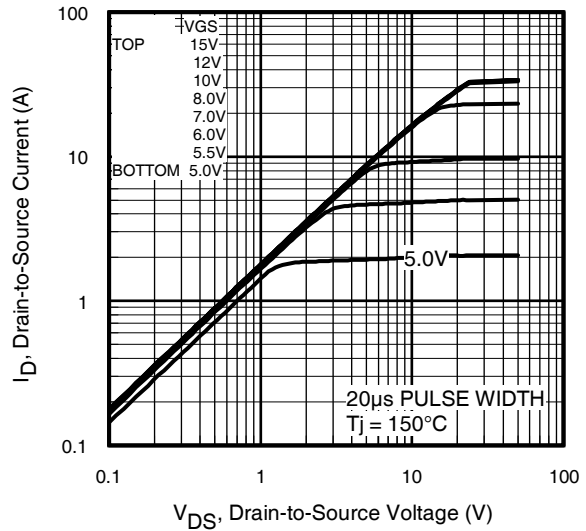


Fig 2. Typical Output Characteristics

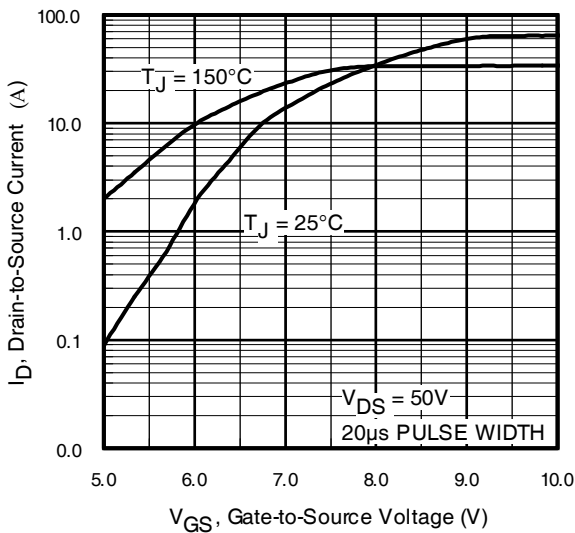


Fig 3. Typical Transfer Characteristics

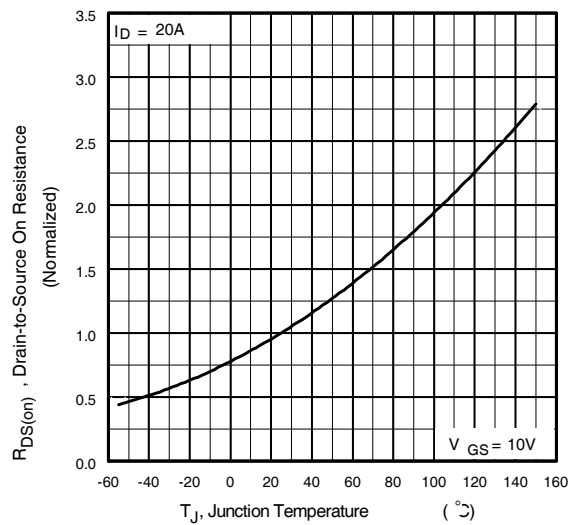


Fig 4. Normalized On-Resistance Vs. Temperature

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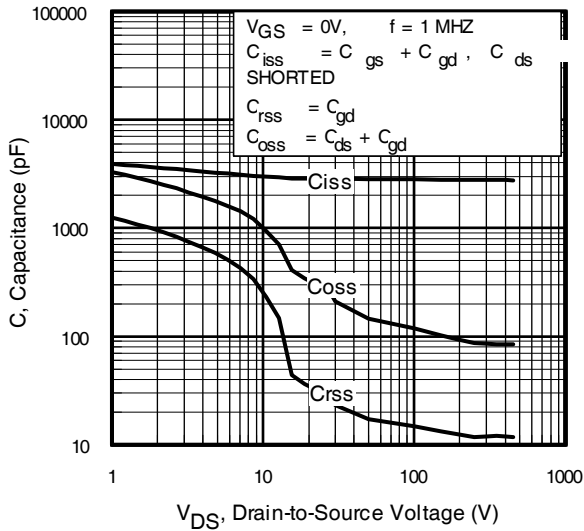


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

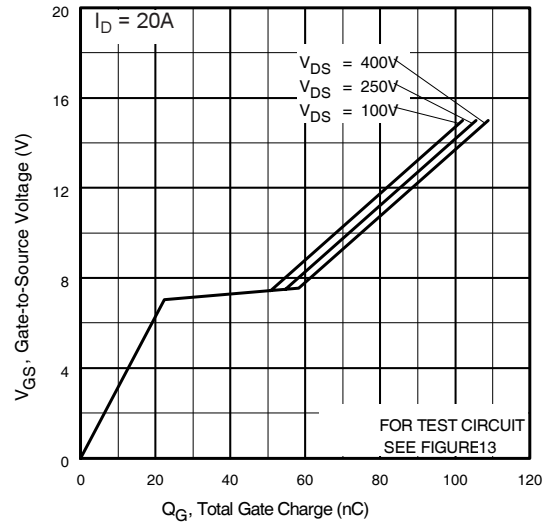


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

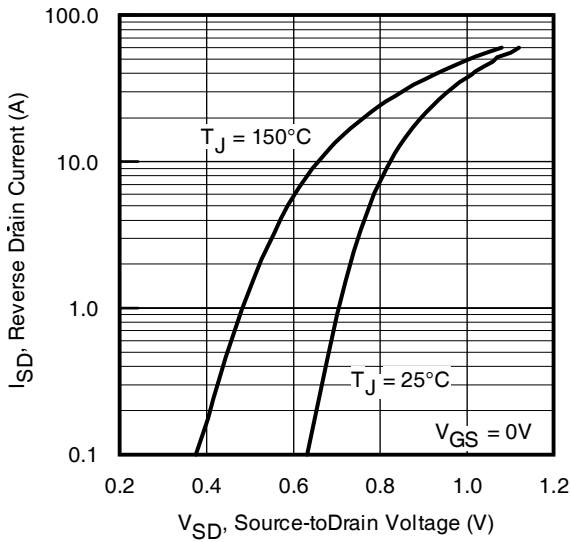


Fig 7. Typical Source-Drain Diode Forward Voltage

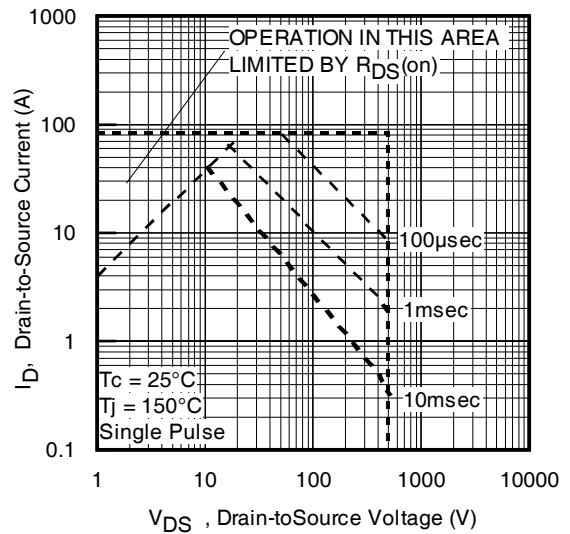


Fig 8. Maximum Safe Operating Area

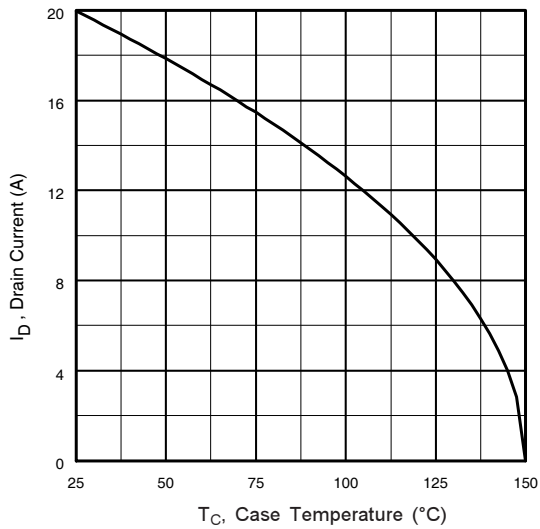


Fig 9. Maximum Drain Current Vs. Case Temperature

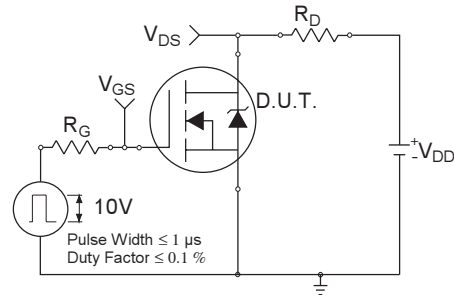


Fig 10a. Switching Time Test Circuit



Fig 10b. Switching Time Waveforms

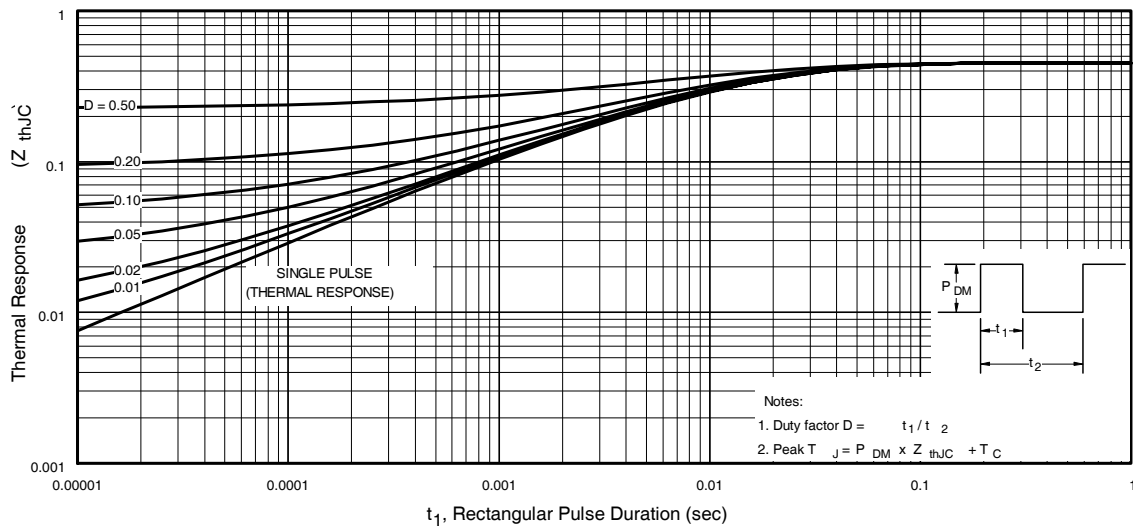


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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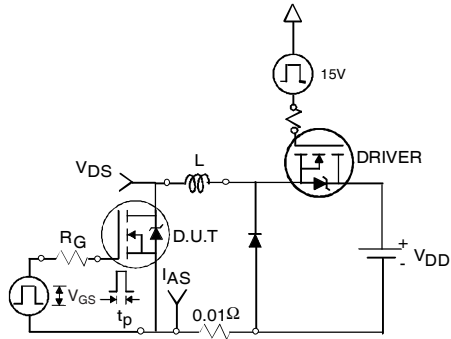


Fig 12a. Unclamped Inductive Test Circuit

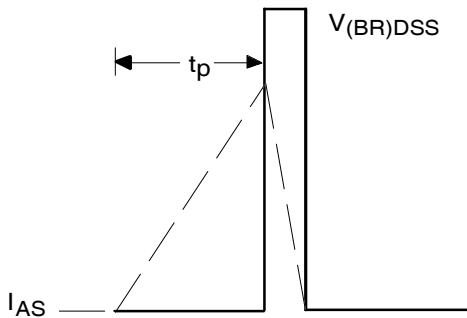


Fig 12b. Unclamped Inductive Waveforms

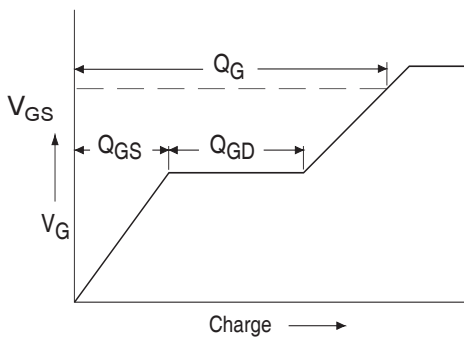


Fig 13a. Basic Gate Charge Waveform

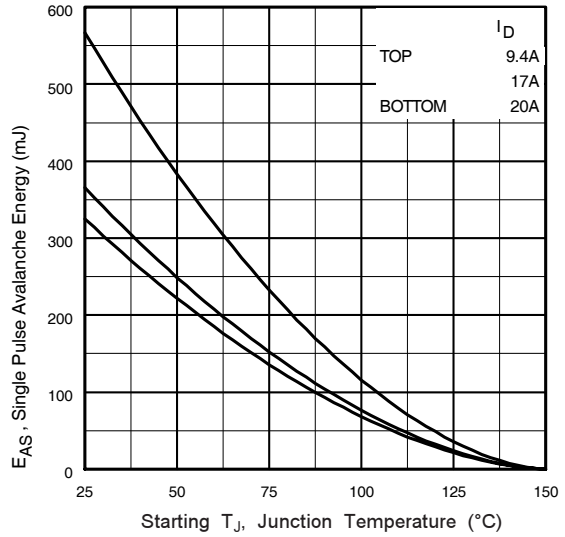


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

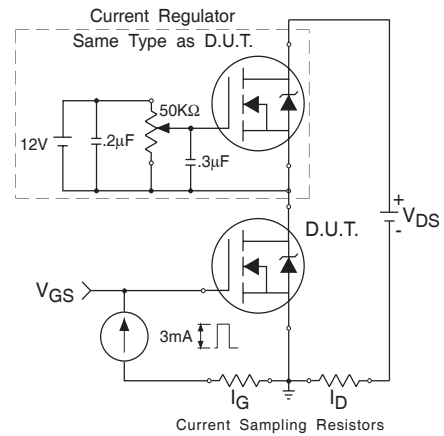


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



* $V_{GS} = 5V$ for Logic Level Devices

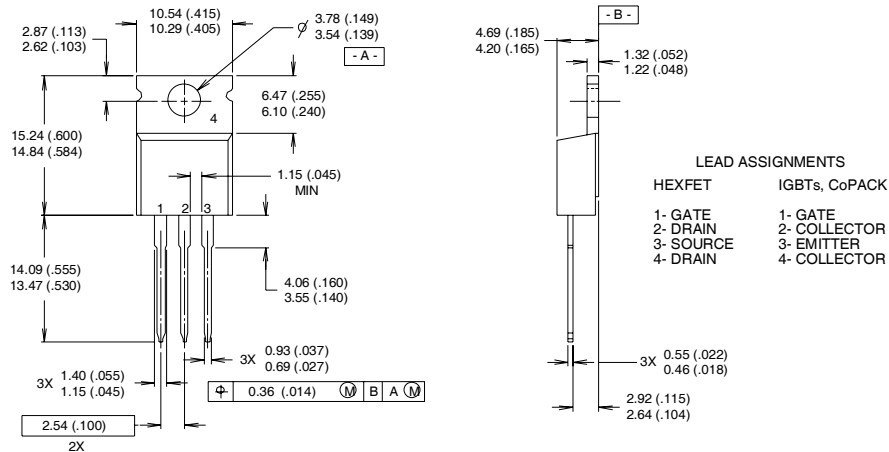
Fig 14. For N-Channel HEXFETS

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International
IR Rectifier

TO-220AB Package Outline

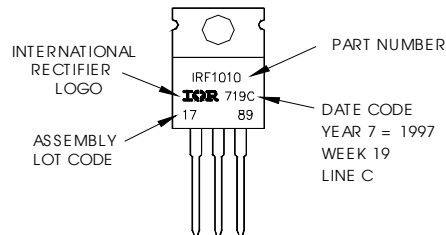
Dimensions are shown in millimeters (inches)



- NOTES:
- 1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982.
 - 2 CONTROLLING DIMENSION : INCH
 - 3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220AB.
 - 4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010
 LOT CODE 1789
 ASSEMBLED ON WW 19, 1997
 IN THE ASSEMBLY LINE "C"
Note: "P" in assembly line
 position indicates "Lead-Free"



Data and specifications subject to change without notice.
 This product has been designed and qualified for the Industrial market.
 Qualification Standards can be found on IR's Web site.

International
IR Rectifier

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